Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/721,908	TAKEUCHI ET AL.
Examiner	Art Unit
Huan H. Tran	2861

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	SEAR	CHED	
Class	Subclass	Date	Examiner
347	230,231	6/17/2005	ннт
347	243,244	6/17/2005	ННТ
347	258-261	6/17/2005	ннт
359	642,708	6/17/2005	ннт
359	726,728	6/17/2005	ннт

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

	ARCH NOTES SEARCH STRATE	EGY)
	DATE	EXMR
EAST	6/17/20	005 HHT
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